

MOS FIELD EFFECT TRANSISTOR 2SK3055

SWITCHING N-CHANNEL POWER MOS FET INDUSTRIAL USE

DESCRIPTION

This product is N-Channel MOS Field Effect Transistor designed for high current switching applications.

ORDERING INFORMATION

PART NUMBER	PACKAGE		
2SK3055	Isolated TO-220		

FEATURES

• Low On-State Resistance

 $R_{DS(on)1} = 34 \text{ m}\Omega$ MAX. (Vgs = 10 V, ID = 15 A)

RDS(on)2 = 50 m Ω MAX. (VGS = 4.0 V, ID = 15 A)

- Low Ciss : Ciss = 920 pF TYP.
- Built-in Gate Protection Diode
- Isolated TO-220 package

ABSOLUTE MAXIMUM RATINGS (TA = 25 °C)

Drain to Source Voltage	VDSS	60	V	
Gate to Source Voltage	VGSS(AC)	±20	V	
Gate to Source Voltage	VGSS(DC)	+20, -10	V	
Drain Current (DC)	I _{D(DC)}	±30	Α	
Drain Current (Pulse) Note1	D(pulse)	±100	Α	
Total Power Dissipation (Tc = 25°C)	P⊤	25	W	
Total Power Dissipation (T _A = 25°C)	PT	2.0	W	
Channel Temperature	Tch	150	°C	
Storage Temperature	Tstg	-55 to +150	°C	
Single Avalanche Current Note2	las	15	Α	
Single Avalanche Energy Note2	Eas	22.5	mJ	

Notes 1. PW \leq 10 μ s, Duty cycle \leq 1 %

2. Starting T_{ch} = 25 °C, R_G = 25 Ω , V_{GS} = 20 V \rightarrow 0 V

THERMAL RESISTANCE

Channel to Case	Rth(ch-C)	5.0	°C/W	
Channel to Ambient	Rth(ch-A)	62.5	°C/W	

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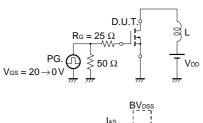
Not all devices/types available in every country. Please check with local NEC representative for availability and additional information.

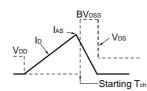


ELECTRICAL CHARACTERISTICS (TA = 25 °C)

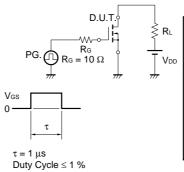
CHARACTERISTICS	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT
Drain to Source On-state Resistance	RDS(on)1	Vgs = 10 V, ID = 15 A		24	34	mΩ
	RDS(on)2	Vgs = 4.0 V, ID = 15 A		35	50	mΩ
Gate to Source Cut-off Voltage	V _{GS(off)}	V _{DS} = 10 V, I _D = 1 mA	1.0	1.6	2.0	V
Forward Transfer Admittance	yfs	V _{DS} = 10 V, I _D = 15 A	8.0	20		S
Drain Leakage Current	Ipss	Vps = 60 V, Vgs = 0 V			10	μΑ
Gate to Source Leakage Current	lgss	Vgs = ±20 V, Vps = 0 V			±10	μΑ
Input Capacitance	Ciss	Vps = 10 V		920		pF
Output Capacitance	Coss	V _G S = 0 V		280		pF
Reverse Transfer Capacitance	Crss	f = 1 MHz		120		pF
Turn-on Delay Time	td(on)	ID = 15 A		25		ns
Rise Time	tr	V _{GS(on)} = 10 V		300		ns
Turn-off Delay Time	td(off)	VDD = 30 V		70		ns
Fall Time	tf	$R_G = 10 \Omega$		120		ns
Total Gate Charge	Q _G	ID = 30 A		25		nC
Gate to Source Charge	Qgs	VDD = 48 V		3.3		nC
Gate to Drain Charge	Q _{GD}	V _{GS(on)} = 10 V		7.0		nC
Body Diode Forward Voltage	VF(S-D)	IF = 30 A, VGS = 0 V		1.0		V
Reverse Recovery Time	trr	If = 30 A, V _G s = 0 V		45		ns
Reverse Recovery Charge	Qrr	di/dt = 100 A/μs		60		nC

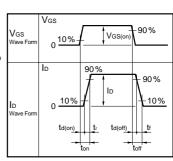
TEST CIRCUIT 1 AVALANCHE CAPABILITY





TEST CIRCUIT 2 SWITCHING TIME

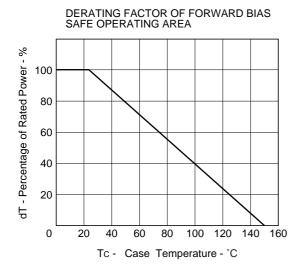


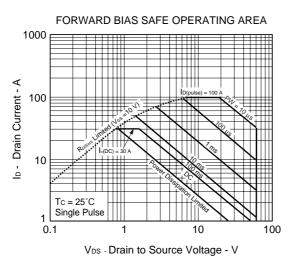


TEST CIRCUIT 3 GATE CHARGE

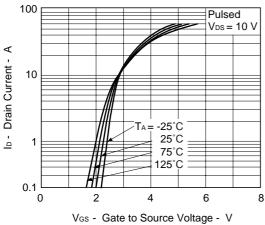


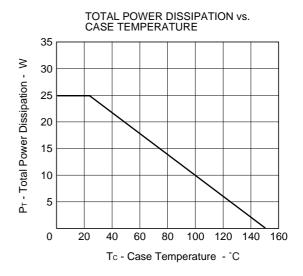
TYPICAL CHARACTERISTICS (TA = 25 °C)

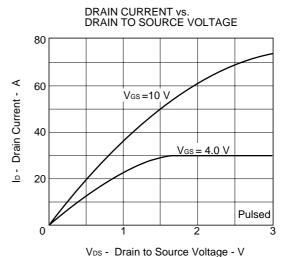




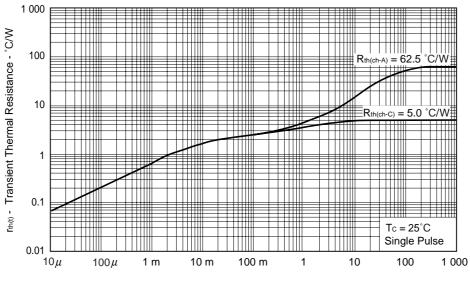
FORWARD TRANSFER CHARACTERISTICS 100 Pulsed





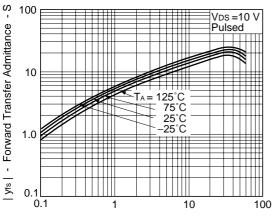


TRANSIENT THERMAL RESISTANCE vs. PULSE WIDTH

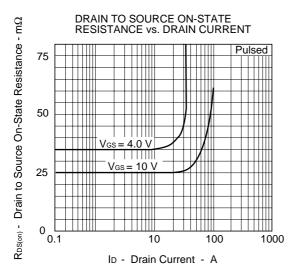


PW - Pulse Width - s

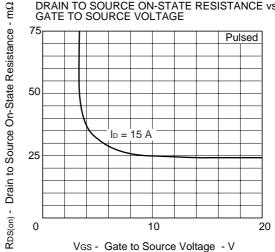
FORWARD TRANSFER ADMITTANCE vs. DRAIN CURRENT

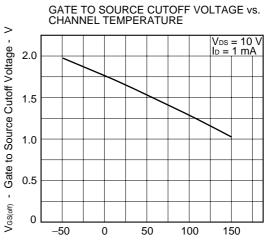


ID - Drain Current - A



DRAIN TO SOURCE ON-STATE RESISTANCE vs. GATE TO SOURCE VOLTAGE



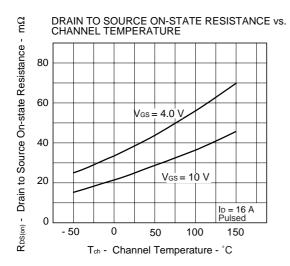


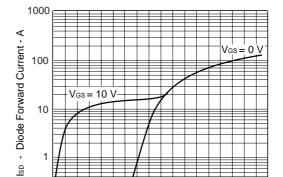
Tch - Channel Temperature - °C

Pulsed

1.5







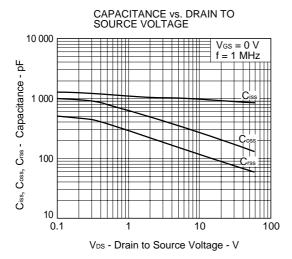
1.0

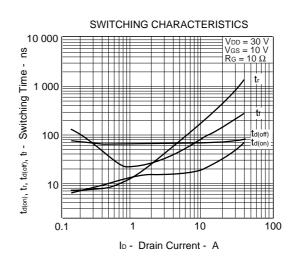
V_{SD} - Source to Drain Voltage - V

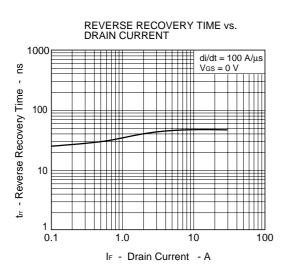
0.5

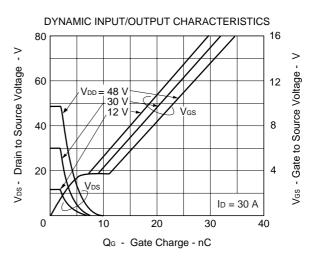
0.1

SOURCE TO DRAIN DIODE FORWARD VOLTAGE

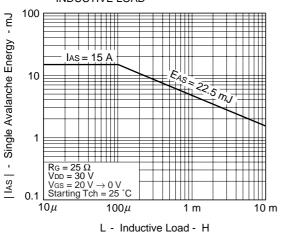




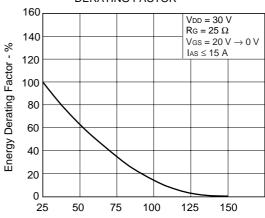




SINGLE AVALANCHE ENERGY vs. INDUCTIVE LOAD



SINGLE AVALANCHE ENERGY DERATING FACTOR

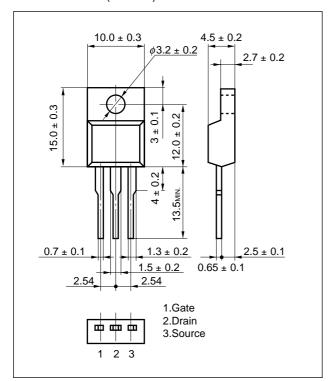


Starting Tch - Starting Channel Temperature - °C

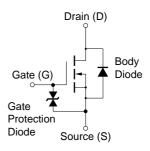


PACKAGE DRAWING (Unit: mm)

Isolated TO-220 (MP-45F)



EQUIVALENT CIRCUIT



Remark The diode connected between the gate and source of the transistor serves as a protector against ESD. When this device actually used, an additional protection circuit is externally required if a voltage exceeding the rated voltage may be applied to this device.

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